



## CORRECTED FORM PTO-1449

SHEET 1 OF 1

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 255291US40PCT		SERIAL NO. 10/502,045		
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Atsushi KUDO, et al.				
				FILING DATE January 10, 2005		GROUP 1797		
				U.S. PATENT DOCUMENTS				
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE		
	AA	US 4,595,662	06/17/1986	Shigeru MOCHIDA, et al.				
	AB	US 4,953,627	09/04/1990	Toshikazu ITO, et al.				
	AG	US 4,357,987	11/09/1982	Isao ODA, et al.				
	AC	US 4,304,585	12/08/1981	Isao ODA, et al.				
	AF	US 2005/0076626 A1	04/14/2005	Atsushi KUDO, et al.				
	AF							
	AG							
	AH							
	AI							
	AJ							
	AK							
	AJ							
	AM							
AN								
FOREIGN PATENT DOCUMENTS								
	DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION				
				YES	NO			
	AO	JP 2000-279729	10/10/2000	Japan (with English abstract and Unedited Computer-Generated English translation)	X			
	AR	JP 60-141667	07/29/1985	Japan (with English abstract, corresponding to US 4,595,662)		X		
	AO	JP 2-93297	04/04/1990	Japan (with English abstract, corresponding to US 4,953,627)		X		
	AR	JP 55-46338	04/01/1980	Japan (with English abstract, corresponding to US 4,357,987 and US 4,304,585)		X		
	AS	JP 2001-182121	08/19/2001	Japan (with English abstract and Unedited Computer-Generated English translation)	X			
	AT	WO 2003/067042	08/14/2003	WIPO (corresponding to US 2005-0076626)		X		
	AU	WO 03/067041	08/14/2003	WIPO (copy not available, corresponding to US 2005-0076626)				
	AV							
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)								
	AW							
	AX							
	AY							
	AZ							
					<input type="checkbox"/> Additional References sheet(s) attached			
Examiner /Natasha Young/				Date Considered 07/14/2009				

\*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 326179US40DIV		SERIAL NO. 12/116,503	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Atsushi KUDO, et al.			
				FILING DATE May 7, 2008		GROUP 1797	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
 NY	AA	US 4,595,662	06/17/1986	Shigeru MOCHIDA, et al.			
	AB	US 4,953,627	09/04/1990	Toshikazu ITO, et al.			
	AC	US 4,357,987	11/09/1982	Isao ODA, et al.			
	AD	US 4,304,585	12/08/1981	Isao ODA, et al.			
	AE	US 2005/0076626 A1	04/14/2005	Atsushi KUDO, et al.			
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
AN							
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
 NY	AO	JP 2000-279729	10/10/2000	Japan (with English abstract and Unedited Computer-Generated English translation)	X		
	AP	JP 60-141667	07/26/1985	Japan (with English abstract, corresponding to US 4,595,662)			X
	AQ	JP 2-93297	04/04/1990	Japan (with English abstract, corresponding to US 4,953,627)			X
	AR	JP 55-48338	04/01/1980	Japan (with English abstract, corresponding to US 4,357,987 and US 4,304,585)			X
	AS	JP 2001-182121	06/19/2001	Japan (with English abstract and Unedited Computer-Generated English translation)	X		
	AT	WO 2003/067042	08/14/2003	WIPO (corresponding to US 2005-0076626)			X
	AU	WO 03/067041	08/14/2003	WIPO (copy not available, corresponding to US 2005-0076626)			
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW						
	AX						
	AY						
	AZ						
Examiner /Natasha Young/					<input type="checkbox"/> Additional References sheet(s) attached Date Considered 08/20/2008		

\*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.